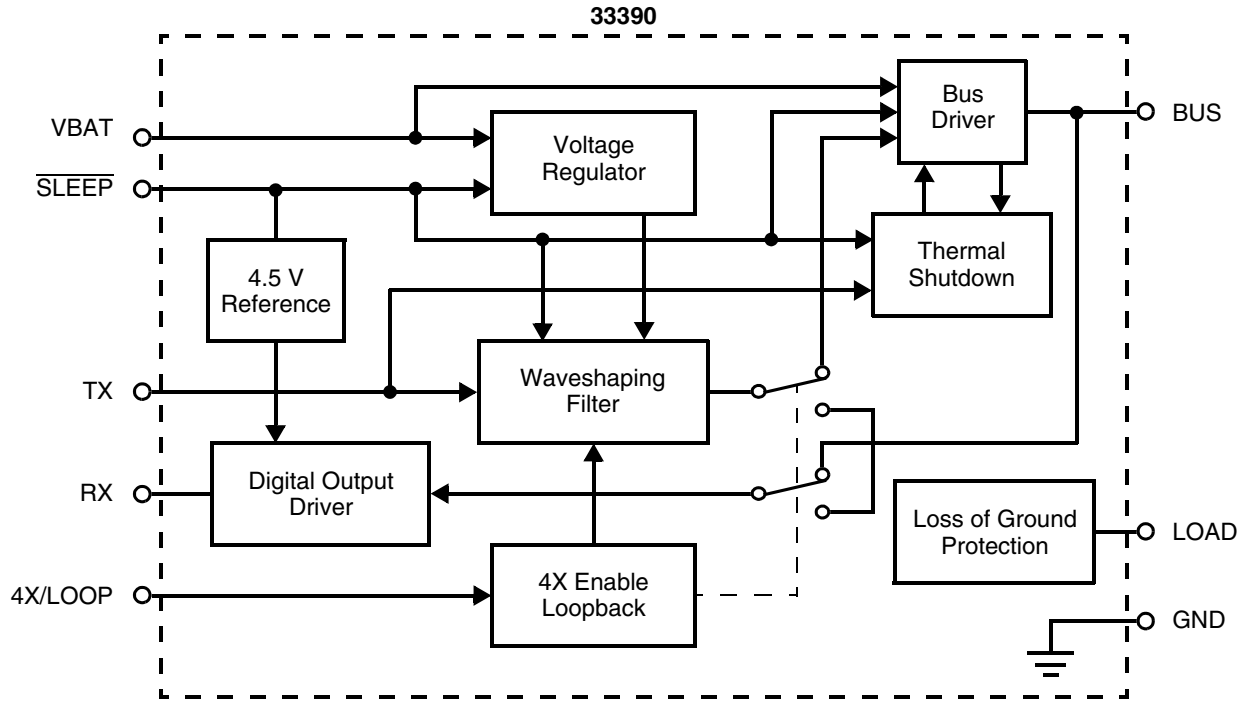




## INTERNAL BLOCK DIAGRAM



**Note** This device contains approximately 400 active transistors and 250 gates.

**Figure 2. 33390 Simplified Internal Block Diagram**

### PIN CONNECTIONS

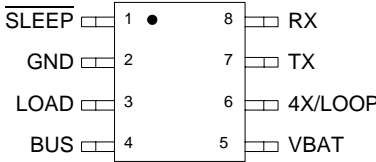


Figure 3. 33390 Pin Connections

Table 1. 33390 Pin Definitions

A functional description of each pin can be found in the Functional Pin Description section beginning on [page 9](#).

Pin Number	Pin Name	Definition
1	$\overline{\text{SLEEP}}$	Enables the transceiver when Logic 1 and disables the transceiver when Logic 0.
2	GND	Device ground pin.
3	LOAD	Accommodates an external pull-down resistor to ground to provide loss of ground protection.
4	BUS	Waveshaped SAE Standard J-1850 Class B transmitter output and receiver input.
5	VBAT	Provides device operating input power.
6	4X/LOOP	Tristate input mode control; Logic 0 = normal waveshaping, Logic 1 = waveshaping disabled for 4X transmitting, high impedance = loopback mode.
7	TX	Serial data input (DI) from the microcontroller to be transmitted onto Bus.
8	RX	Bus received serial data output (DO) sent to the microcontroller.

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## ELECTRICAL CHARACTERISTICS

### MAXIMUM RATINGS

**Table 2. Maximum Ratings**

All voltages are with respect to ground unless otherwise noted. Exceeding these ratings may cause a malfunction or permanent damage to the device.

Ratings	Symbol	Value	Unit
VBAT DC Supply Voltage <sup>(1)</sup>	V <sub>BAT</sub>	-0.3 to 40	V
Input I/O Pins <sup>(2)</sup>	V <sub>I/O(CPU)</sub>	-0.3 to 7.0	V
BUS and LOAD Outputs	V <sub>BUS</sub>	-2.0 to 16	V
ESD Voltage <sup>(3)</sup>			V
Human Body Model	V <sub>ESD1</sub>	±2000	
Machine Model	V <sub>ESD2</sub>	±200	
Storage Temperature	T <sub>STG</sub>	-65 to 150	°C
Operating Ambient Temperature	T <sub>A</sub>	-40 to 125	°C
Operating Junction Temperature	T <sub>J</sub>	-40 to 150	°C
Peak Package Reflow Temperature During Reflow <sup>(4), (5)</sup>	T <sub>PPRT</sub>	Note 5.	°C
Thermal Resistance (Junction-to-Ambient)	R <sub>θJ-A</sub>	180	°C/W

Notes

1. An external series diode must be used to provide reverse battery protection of the device.
2. SLEEP, TX, RX, and 4X/LOOP are normally connected to a microcontroller.
3. ESD1 testing is performed in accordance with the Human Body Model (C<sub>ZAP</sub>=100 pF, R<sub>ZAP</sub>=1500 Ω), ESD2 testing is performed in accordance with the Machine Model (C<sub>ZAP</sub>=200 pF, R<sub>ZAP</sub>=0 Ω).
4. Pin soldering temperature limit is for 10 seconds maximum duration. Not designed for immersion soldering. Exceeding these limits may cause malfunction or permanent damage to the device.
5. Freescale's Package Reflow capability meets Pb-free requirements for JEDEC standard J-STD-020C. For Peak Package Reflow Temperature and Moisture Sensitivity Levels (MSL), Go to [www.freescale.com](http://www.freescale.com), search by part number [e.g. remove prefixes/suffixes and enter the core ID to view all orderable parts. (i.e. MC33xxxD enter 33xxx), and review parametrics.

### STATIC ELECTRICAL CHARACTERISTICS

**Table 3. Static Electrical Characteristics**

Characteristics noted under conditions of  $7.0\text{ V} \leq V_{\text{BAT}} \leq 16\text{ V}$ ,  $-40^{\circ}\text{C} \leq T_{\text{A}} \leq 125^{\circ}\text{C}$ , SLEEP = 5.0 V unless otherwise noted. Typical values reflect the parameter's approximate midpoint average value with  $V_{\text{BAT}} = 13\text{ V}$ ,  $T_{\text{A}} = 25^{\circ}\text{C}$ . All positive currents are into the pin. All negative currents are out of the pin.

Characteristic	Symbol	Min	Typ	Max	Unit
<b>POWER CONSUMPTION</b>					
Operational Battery Current (RMS with Tx = 7.812 kHz Square Wave) BUS Load = 1380 $\Omega$ to GND, 3.6 nF to GND BUS Load = 257 $\Omega$ to GND, 20.2 nF to GND	$I_{\text{BAT(OP1)}}$ $I_{\text{BAT(OP2)}}$	–	3.0 22.4	11.5 32	mA
Battery Bus Low Input Current After SLEEP Toggle Low to High; Prior to Tx Toggling After Tx Toggle High to Low	$I_{\text{BAT(BUS L1)}}$ $I_{\text{BAT(BUS L2)}}$	–	1.1 6.4	3.0 8.5	mA
Sleep State Battery Current $V_{\text{SLEEP}} = 0\text{ V}$	$I_{\text{BAT(SLEEP)}}$	–	38.2	65	$\mu\text{A}$

#### BUS

BUS Input Receiver Threshold <sup>(6)</sup> Threshold High (Bus Increasing until $Rx \geq 3.0\text{ V}$ ) Threshold Low (Bus Decreasing until $Rx \leq 3.0\text{ V}$ ) Threshold in Sleep State ( $\text{SLEEP} = 0\text{ V}$ ) Hysteresis ( $V_{\text{BUS(IH)}} - V_{\text{BUS(IL)}}$ , $\text{SLEEP} = 0\text{ V}$ )	$V_{\text{BUS(IH)}}$ $V_{\text{BUS(IL)}}$ $BUS_{\text{TH(SLEEP)}}$ $V_{\text{BUS(HYST)}}$	4.25 – 2.4 0.1	3.9 3.7 3.0 0.2	– 3.5 3.4 0.6	V
BUS-Out Voltage ( $257\ \Omega \leq R_{\text{BUS(L)}} \leq 1380\ \Omega$ ) $8.2\text{ V} \leq V_{\text{BAT}} \leq 16\text{ V}$ , Tx = 5.0 V $4.25\text{ V} \leq V_{\text{BAT}} \leq 8.2\text{ V}$ , Tx = 5.0 V Tx = 0 V	$V_{\text{BUS(OUT1)}}$ $V_{\text{BUS(OUT2)}}$ $V_{\text{BUS(OUT3)}}$	6.25 $V_{\text{BAT}} - 1.6$ –	6.9 – 0.27	8.0 $V_{\text{BAT}}$ 0.7	V
BUS Short Circuit Output Current Tx = 5.0 V, $-2.0\text{ V} \leq V_{\text{BUS}} \leq 4.8\text{ V}$	$I_{\text{BUS(SHORT)}}$	60	129	170	mA
BUS Leakage Current $-2.0\text{ V} \leq V_{\text{BUS}} \leq 0\text{ V}$ $0\text{ V} \leq V_{\text{BUS}} \leq V_{\text{BAT}}$	$I_{\text{BUS(LEAK1)}}$ $I_{\text{BUS(LEAK2)}}$	-500 –	-55 189	– 500	$\mu\text{A}$
BUS Thermal Shutdown <sup>(7)</sup> (Tx = 5.0 V, $I_{\text{BUS}} = -0.1\text{ mA}$ ) Increase Temperature until $V_{\text{BUS}} \leq 2.5\text{ V}$	$T_{\text{BUS(LIM)}}$	150	170	190	$^{\circ}\text{C}$
BUS Thermal Shutdown Hysteresis <sup>(8)</sup> $T_{\text{BUS(LIM)}} - T_{\text{BUS(REEN)}}$	$T_{\text{BUS(LIMHYS)}}$	10	12	15	$^{\circ}\text{C}$
BUS and LOAD Current with Loss of $V_{\text{BAT}}$ or GND ( $I_{\text{BAT}} = 0\ \mu\text{A}$ ) (see <a href="#">Figure 4</a> ) $-18\text{ V} \leq V_{\text{BUS}} \leq 9.0\text{ V}$ $-18\text{ V} \leq V_{\text{LOAD}} \leq 9.0\text{ V}$	$I_{\text{BUS(LOSS)}}$ $I_{\text{LOAD(LOSS)}}$	–	0.00 0.00	0.1 0.1	mA

#### Notes

- Typical threshold value is the approximate actual occurring switch point value with  $V_{\text{BAT}} = 13\text{ V}$ ,  $T_{\text{A}} = 25^{\circ}\text{C}$ .
- Device characterized but not production tested for thermal shutdown.
- Device characterized but not production tested for thermal shutdown hysteresis.

**Table 3. Static Electrical Characteristics (continued)**

Characteristics noted under conditions of  $7.0\text{ V} \leq V_{\text{BAT}} \leq 16\text{ V}$ ,  $-40^\circ\text{C} \leq T_A \leq 125^\circ\text{C}$ , SLEEP = 5.0 V unless otherwise noted. Typical values reflect the parameter's approximate midpoint average value with  $V_{\text{BAT}} = 13\text{ V}$ ,  $T_A = 25^\circ\text{C}$ . All positive currents are into the pin. All negative currents are out of the pin.

Characteristic	Symbol	Min	Typ	Max	Unit
<b>BUS (CONTINUED)</b>					
LOAD Output $I_L = 6.0\text{ mA}$	$L_{\text{ON}}$	–	0.07	0.2	V
Unpowered LOAD Output $V_{\text{BAT}} = 0\text{ V}$ , $I_L = 6.0\text{ mA}$	$L_{\text{DIO}}$	0.3	0.56	0.9	V
<b>TX</b>					
Tx Input Voltage Tx Input Logic Low Level Tx Input Logic High Level	$V_{\text{Tx(IL)}}$ $V_{\text{Tx(IH)}}$	– 3.5	– –	0.8 –	V
Tx Input Current $V_{\text{Tx}} = 5.0\text{ V}$ $V_{\text{Tx}} = 0\text{ V}$	$I_{\text{Tx(IH)}}$ $I_{\text{Tx(IL)}}$	50 -2.0	106 0.23	200 2.0	$\mu\text{A}$
<b>LOOP</b>					
4X/LOOP Input Current $V_{4\text{X}/\text{LOOP}} = 0\text{ V}$ (Normal Mode) $V_{4\text{X}/\text{LOOP}} = 5.0\text{ V}$ (4X Mode)	$I_{4\text{X}/\text{LOOP(IL)}}$ $I_{4\text{X}/\text{LOOP(IH)}}$	-200 -200	-60 110	200 200	$\mu\text{A}$
4X/LOOP Input Threshold (Tx = 4096 Hz Square Wave) Normal Mode to Loopback Mode Loopback Mode to 4X Mode	$V_{4\text{X}/\text{LOOP(IL)}}$ $V_{4\text{X}/\text{LOOP(IH)}}$	1.1 3.2	1.31 3.43	1.5 3.6	V
<b>RX</b>					
Rx Output Voltage Low $V_{\text{BUS}} = 0\text{ V}$ , $I_{\text{Rx}} = 1.6\text{ mA}$	$V_{\text{Rx(LOW)}}$	0.01	0.18	0.4	V
Rx Output Voltage High $V_{\text{BUS}} = 7.0\text{ V}$ , $I_{\text{Rx}} = -200\text{ }\mu\text{A}$	$V_{\text{Rx(HIGH)}}$	4.25	4.58	4.75	V
Rx Output Current $V_{\text{Rx}} = \text{High}$ ; Short Circuit Protection Limits	$I_{\text{Rx}}$	2.0	3.67	8.0	mA
<b>SLEEP</b>					
SLEEP Input Current $V_{\text{SLEEP}} = 0\text{ V}$ $V_{\text{SLEEP}} = 5.0\text{ V}$	$I_{\text{SLEEP(IL)}}$ $I_{\text{SLEEP(IH)}}$	– 1.0	-0.23 6.21	-2.0 20	$\mu\text{A}$













“start of frame” bit has been transmitted, the secondary node transmitting the most consecutive logic [0] bits will be granted sole transmission access to the bus for that message.

**Loss of Assembly Ground Connection**

The definition of a loss of assembly ground condition at the device level is that all pins of the 33390, with the exception of BUS and LOAD, see a very low impedance to VBAT.

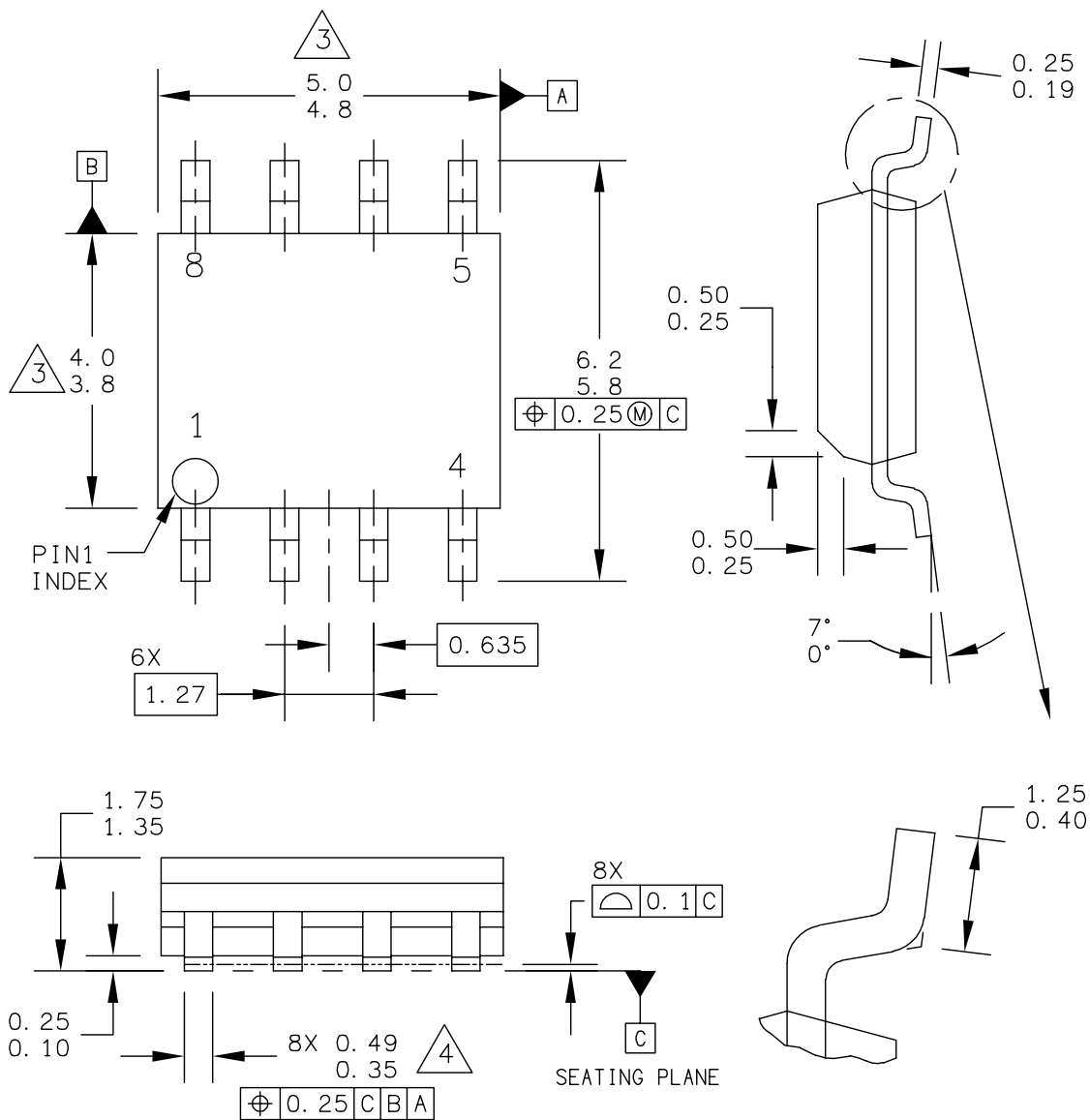
The LOAD pin of the device has an internal transistor switch connected to it that is normally saturated to ground. This pulls the LOAD-side of the external resistor (tied from BUS to LOAD) to ground under normal conditions. The LOAD pin switch is essentially that of an “upside down” FET, which is normally biased “on” so long as module ground is present and biased “off” when loss-of-ground occurs. When a loss of assembly ground occurs, the load transistor switch is self-biased “off”, allowing no more than 100 µA of leakage current

to flow in the LOAD pin. During such a loss of assembly ground condition, the BUS and LOAD pins exhibit a high impedance to VBAT; all other pins will exhibit a low impedance to V<sub>BAT</sub>. During this condition the BUS pin is prevented from sourcing any current or loading the bus, which would cause a corruption of any data being transmitted on the bus. While a particular assembly is experiencing a loss of ground, all other assembly nodes are permitted to function normally. It should be noted that with other nodes existing on the bus, the bus will always have some minimum/maximum impedance to ground as shown in [Table 5](#), page [10](#).

**Loss of Assembly Battery Connection**

The definition of a loss of assembly battery condition at the device level is that the VBAT pin of the 33390 sees an infinite impedance to VBAT, but there is some undefined impedance between these pins and ground.

**PACKAGE DIMENSIONS**

 For the most current package revision, visit [www.freescale.com](http://www.freescale.com) and perform a keyword search using the 98A listed below.


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		CASE NUMBER: 751-07	07 APR 2005	
		STANDARD: JEDEC MS-012AA		

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